

Substitute for Form 1449 A & B/PTO  <b><u>INFORMATION DISCLOSURE</u></b> <b><u>STATEMENT BY APPLICANT</u></b>  <i>(use as many sheets as necessary)</i>				<i>Complete if Known</i>	
				Application Number	10/572,957
				Confirmation Number	4788
				Filing Date	March 21, 2006
				First Named Inventor	Toshiaki KAKINAMI
				Art Unit	Unknown
				Examiner Name	Unkown
Sheet	1	of	1	Attorney Docket Number	Q92639

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code <sup>2</sup> (if known)		
		US			
		US			
		US			
		US			
		US			
		US			

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation <sup>6</sup>
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)			
		JP	2003-168198	A	06-13-2003	TOYOTA MOTOR CORP, et al.	w/ English Abstract
		JP	2003-187227	A	07-04-2003	AISIN SEIKI CO LTD, et al.	w/ English Abstract
		JP	2003-187252	A	07-04-2003	AISIN SEIKI CO LTD, et al.	w/ English Abstract
		JP	2003-178399	A	06-27-2003	AISIN SEIKI CO LTD	w/ English Abstract

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation <sup>6</sup>
		HIDEYUKI TAMURA, "Introduction to Computer Image Processing", March 10, 1985, pp. 127-128, first issue, published by Soken Shuppan.	w/ brief English Translation
		MARTIN A. FISCHLER, et al., "Random Sample Consensus: A Paradigm for Model Fitting with Applications to Image Analysis and Automated Cartography", 1981, pp. 381-395, vol. 24(6), published by Graphics and Image Processing.	
		RICHARD HARTLEY, et al., "Multiple View Geometry in Computer Vision", August 2000, pp. 101-107, published by Cambridge University Press.	

Examiner Signature		Date Considered	
--------------------	--	-----------------	--

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>See Kind Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov), MPEP 901.04 or follow the hyperlink from the title of the document to the intranet. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to indicate here if English language Translation is attached.